

•General Description

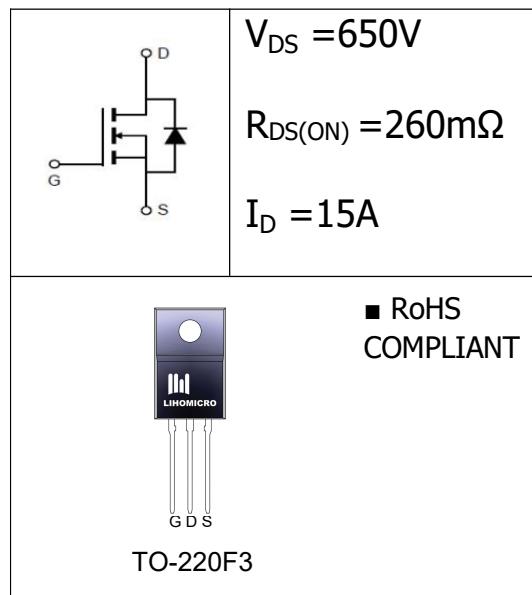
The SJ MOSFET LH65R260 has the low $R_{DS(on)}$, low gate charge, fast switching and excellent avalanche characteristics. This device offers extremely fast and robust body diode, and is suitable for telecom and power supplies.

•Features

- Much lower $R_{DS(on)} \cdot A$ performance for On-state efficiency
- Much lower FOM for fast switching efficiency

•Application

- LED/LCD/PDP TV and monitor Lighting
- Solar/Renewable/UPS-Micro Inverter System
- Power Supplies



•Ordering Information:

Part number	LH65R260		
Package	TO-220F3		
Basic ordering unit (pcs)	1000		
Normal Package Material Ordering Code	LH65R260F3-T0220F3-TU		
Halogen Free Ordering Code	LH65R260F3-T0220F3-TU-HF		

•Absolute Maximum Ratings (TC = 25°C)

PARAMETER	SYMBOL	Value	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	650	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current TC = 25°C TC = 100°C	I_D	15	A
		9	
Pulsed drain current (TC = 25°C, tp limited by Tjmax) ¹	I_D pulse	45	A
Single Pulse Avalanche Energy ¹	I_{AR}	2.4	A
Single Pulse Avalanche Energy ²	E_{AS}	290	mJ
Repetitive Avalanche Energy ¹	E_{AR}	0.44	mJ
Power Dissipation(TC=25°C)	P_D	32	W
Operating Temperature and Storage Temperature Range	T_J/T_{STG}	-55~+150	°C
MOSFET dv/dt ruggedness, $V_{DS}=0...480V$	dv/dt	50	V/ns
Reverse diode dv/dt, $V_{DS}=0...480V, I_{SD} \leq I_D$	dv/dt	15	V/ns

•Electronic Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	650	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.5	--	4.5	V
Drain-source On Resistance ³	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 7.5A$	--	0.24	0.26	Ω
Drain-Source Leakage Current	I_{DSS}	$V_{DS} = 650V, V_{GS} = 0V, T_J = 25^\circ C$	--	--	1	uA
		$V_{DS} = 650V, V_{GS} = 0V, T_J = 125^\circ C$	--	--	100	
Gate-Source Leakage Current	I_{GSS}	$V_{GS} = \pm 30$	--	--	± 100	nA
Forward Transconductance ³	R_G	f=1.0MHz open drain	--	--	12.5	S
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 100V, f = 1.0MHz$	--	1202	--	pF
Output Capacitance	C_{oss}		--	43	--	
Reverse transfer Capacitance	C_{rss}		--	5	--	
Turn -Off Delay Time	$T_d(\text{off})$	$V_{DD} = 400V, I_D = 15.0A, R_G = 25\Omega$	--	100	--	ns
Turn-on delay time	$T_d(\text{on})$		--	25	--	
Rise time	T_r		--	63	--	
Fall time	T_f		--	50	--	
Total Gate Charge	Q_g	$I_D = 15A, V_{DS} = 520V, V_{GS} = 10V$	--	27	---	nC
Gate-to-Source Charge	Q_{gs}		--	5.5	--	
Gate-to-Drain Charge	Q_{gd}		--	10.5	---	
Continuous Diode Forward Current	I_s	$T_J = 25^\circ C, I_s = 15.0A, V_{GS} = 0V$	--	--	15.0	A
Pulsed Diode Forward Current	I_{SM}		--	--	45.0	A
Diode Forward Voltage	V_{SD}	$T_J = 25^\circ C, I_s = 15.0A, V_{GS} = 0V$	--	0.9	1.2	V
Reverse Recovery Time	t_{rr}	$V_{RR} = 400V, I_f = I_s, dI_f/dt = 100A/\mu s$	--	410	--	ns
Reverse Recovery Charge	Q_{rr}		--	4.1	--	uC
Peak Reverse Recovery Current	I_{RRM}		--	20	--	A

•Thermal Characteristics

PARAMETER	SYMBOL	MAX		UNIT
		TO-220F	TO-220	
Thermal Resistance Junction-case	R_{thJC}	3.9	1.2	°C/W
Thermal Resistance Junction-ambient	R_{thJA}	80	62	°C/W

Notes:

1.Repetitive Rating: Pulse width limited by maximum junction temperature.

2. $I_{AS} = 1.8A, V_{DD} = 50V, R_G = 25\Omega$, Starting $T_J = 25^\circ C$

3. Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$

- **Typical Characteristics** $T_J=25^\circ\text{C}$, unless otherwise noted

Figure 1. Output Characteristics

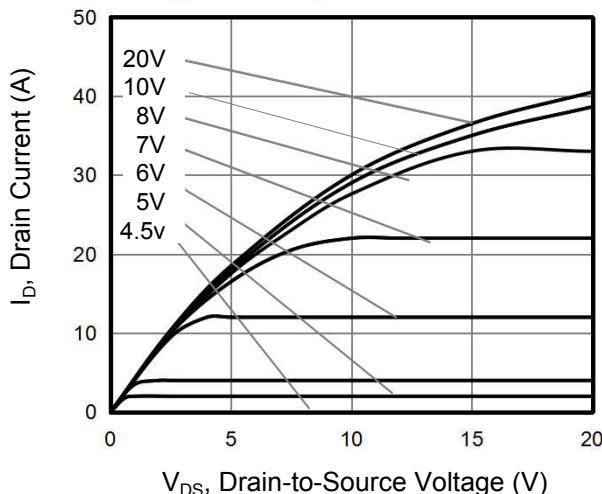


Figure 2. Transfer Characteristics

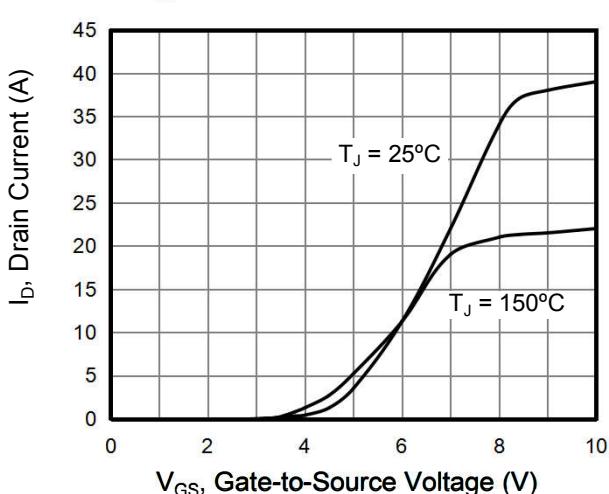


Figure 3. On-Resistance vs. Drain Current

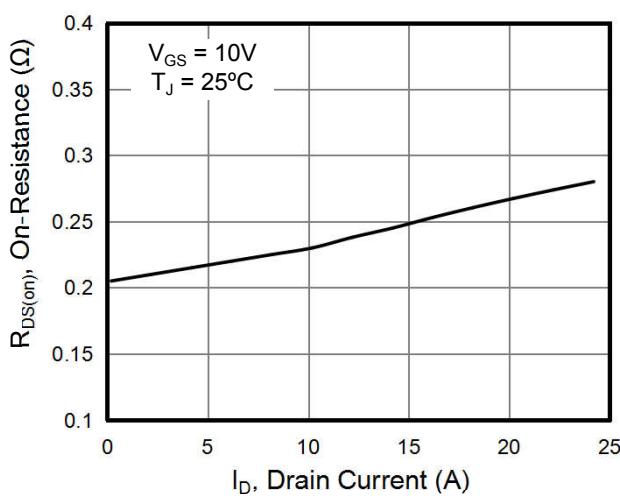


Figure 4. Capacitance

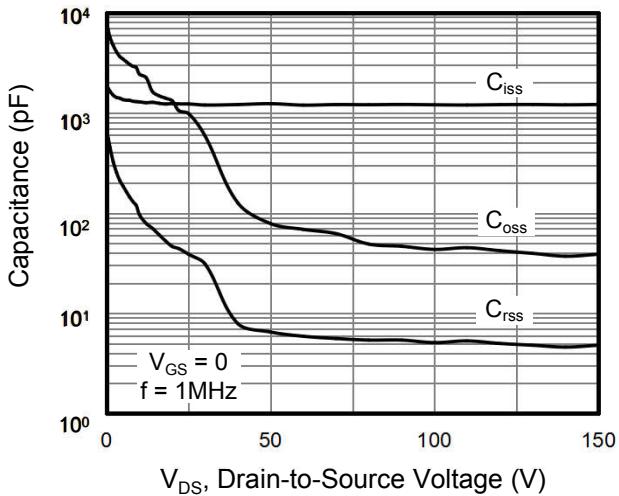


Figure 5. Gate Charge

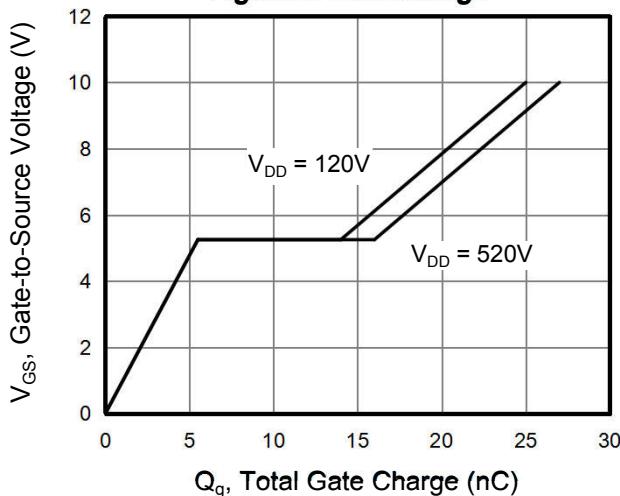
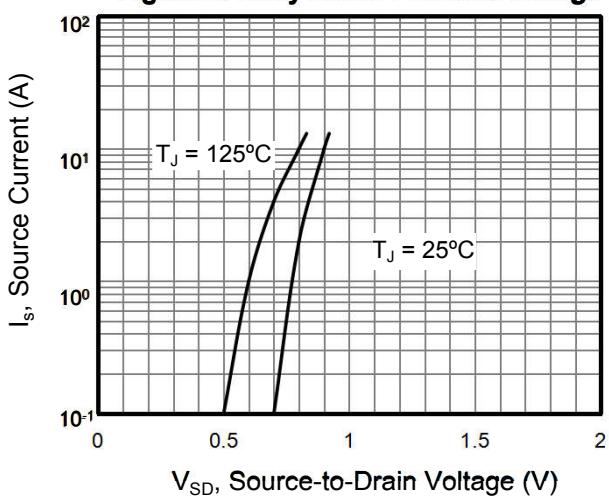
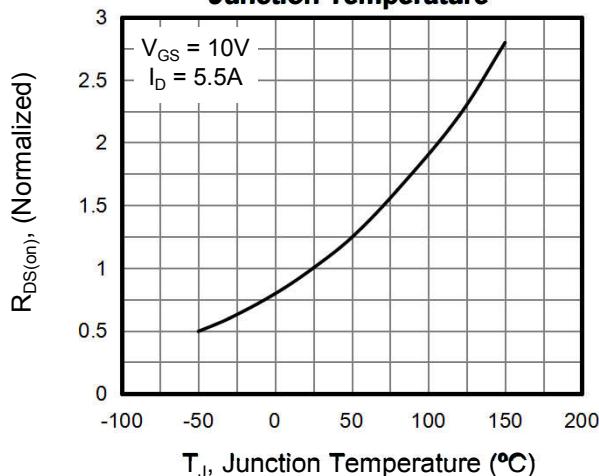
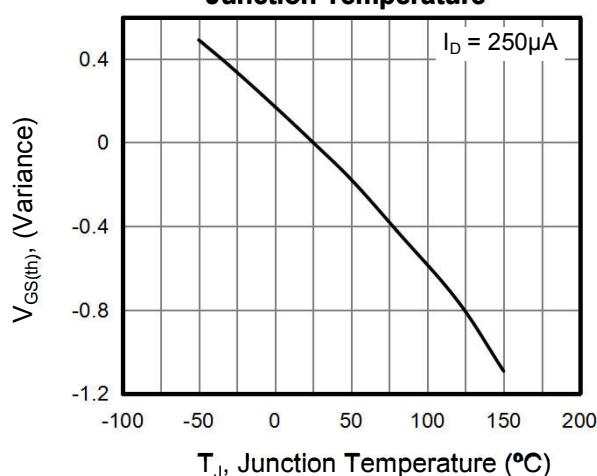
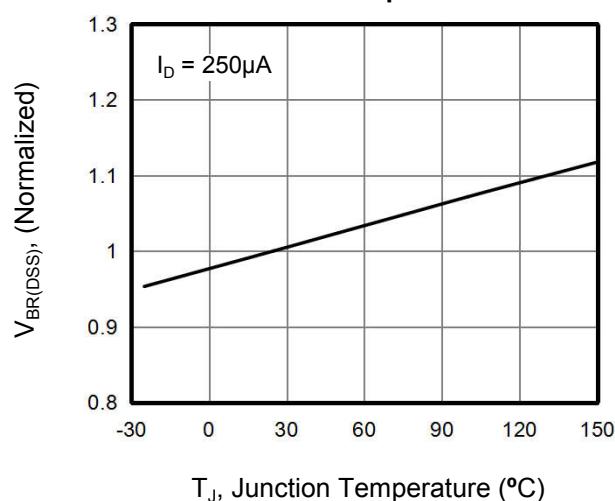
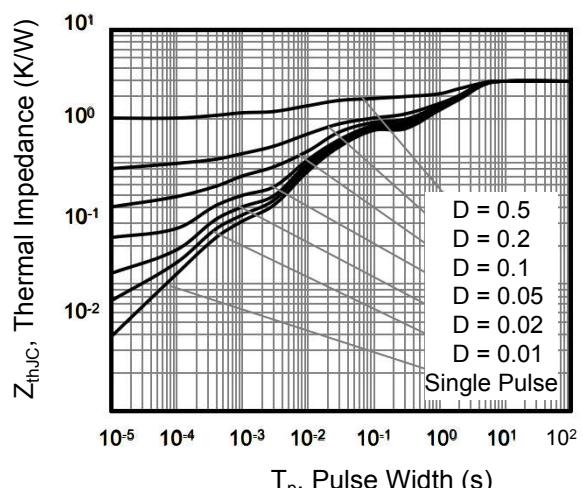
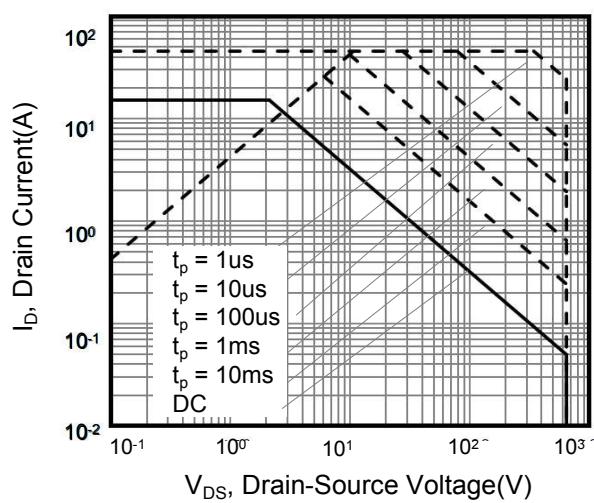
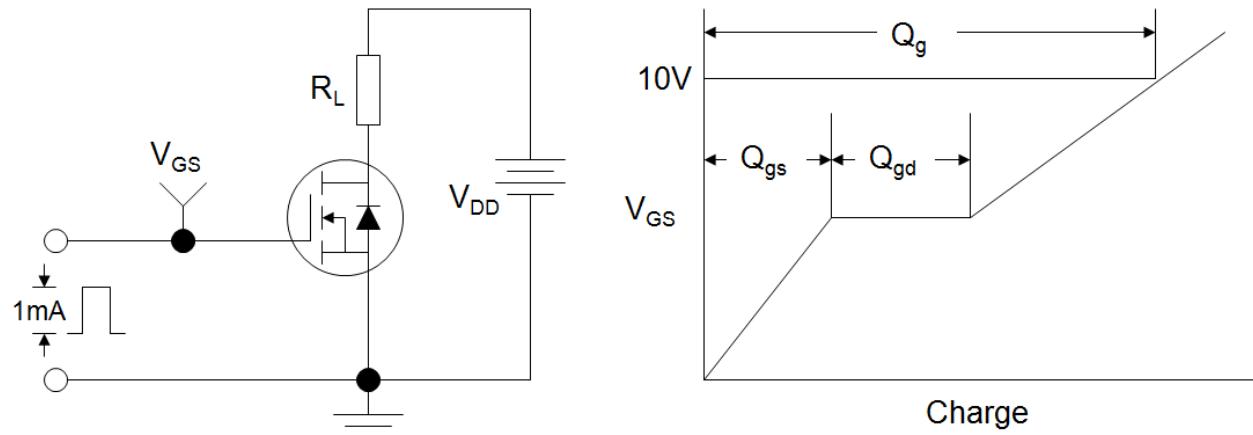
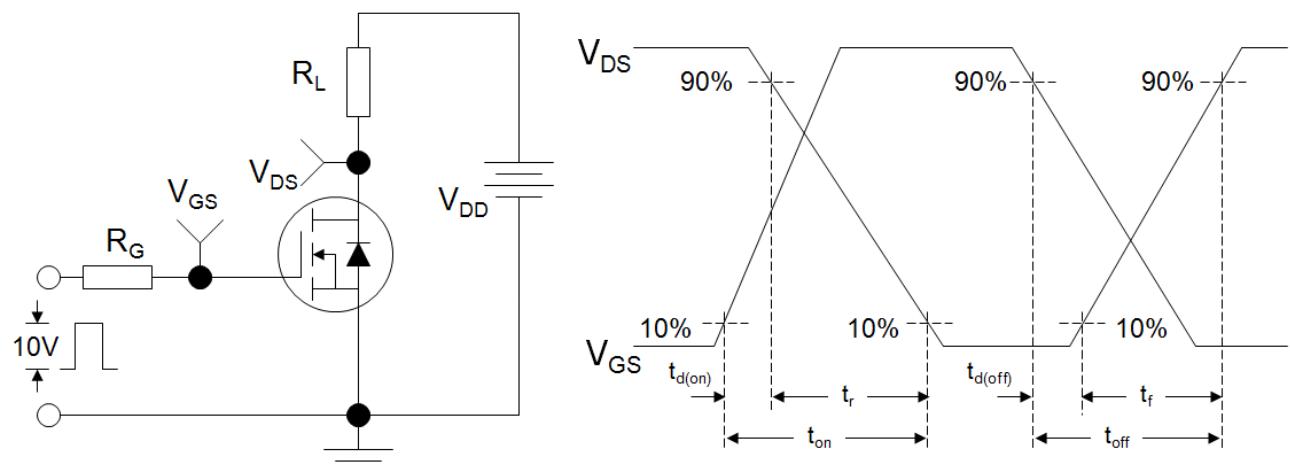
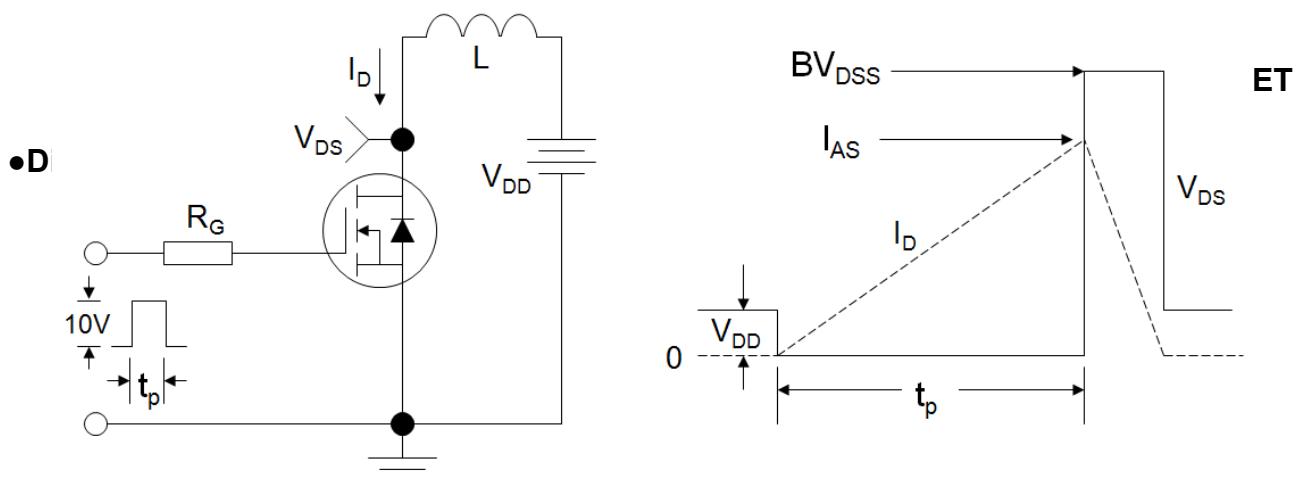


Figure 6. Body Diode Forward Voltage



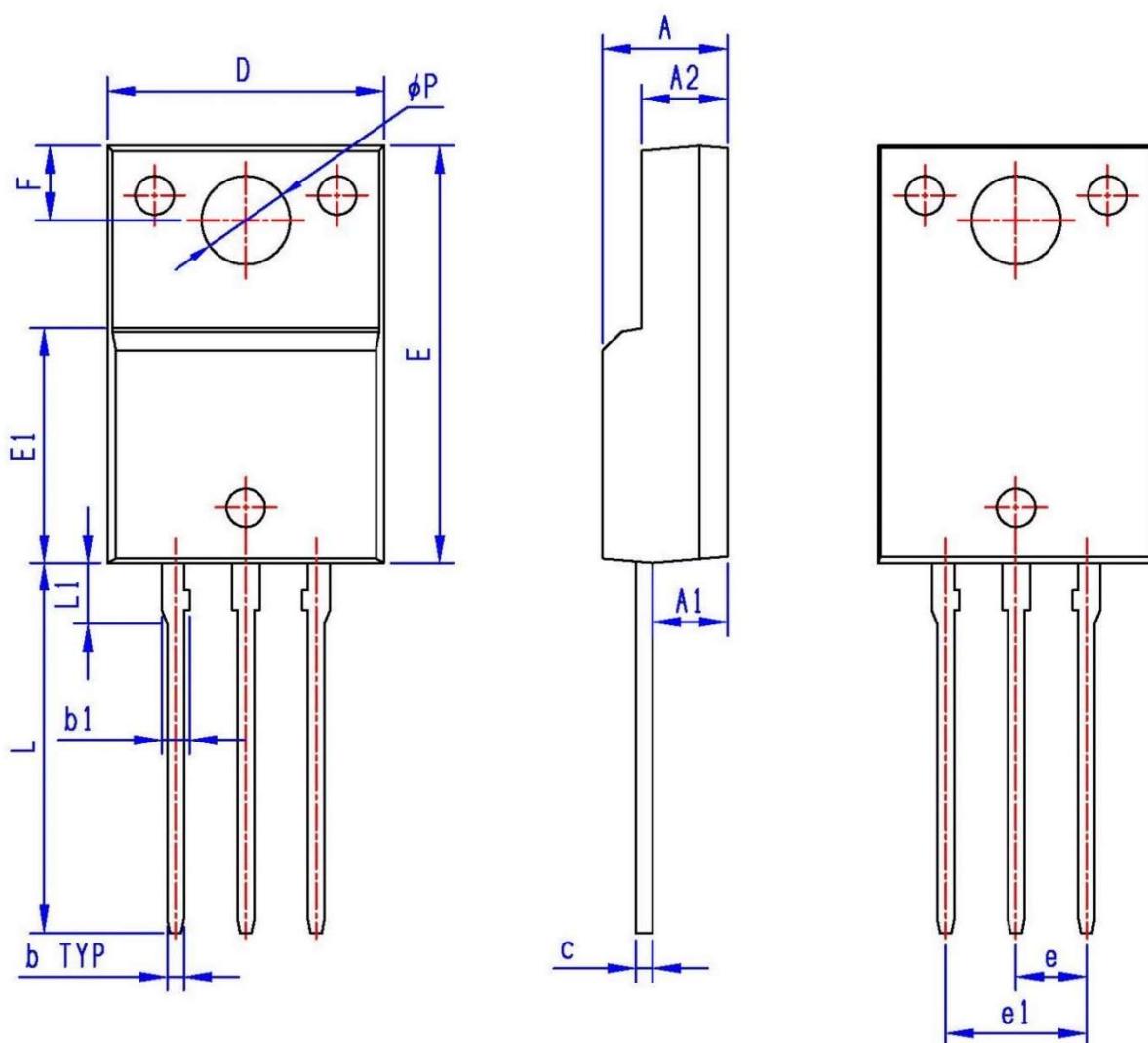
•Typical Characteristics(cont.)
Figure 7. On-Resistance vs. Junction Temperature

Figure 8. Threshold Voltage vs. Junction Temperature

Figure 9. Breakdown voltage vs. Junction Temperature

Figure 10. Transient Thermal Impedance

Figure 11. Safe operation area


•Test Circuit and Waves
Figure A: Gate Charge Test Circuit and Waveform

Figure B: Resistive Switching Test Circuit and Waveform

Figure C: Unclamped Inductive Switching Test Circuit and Waveform


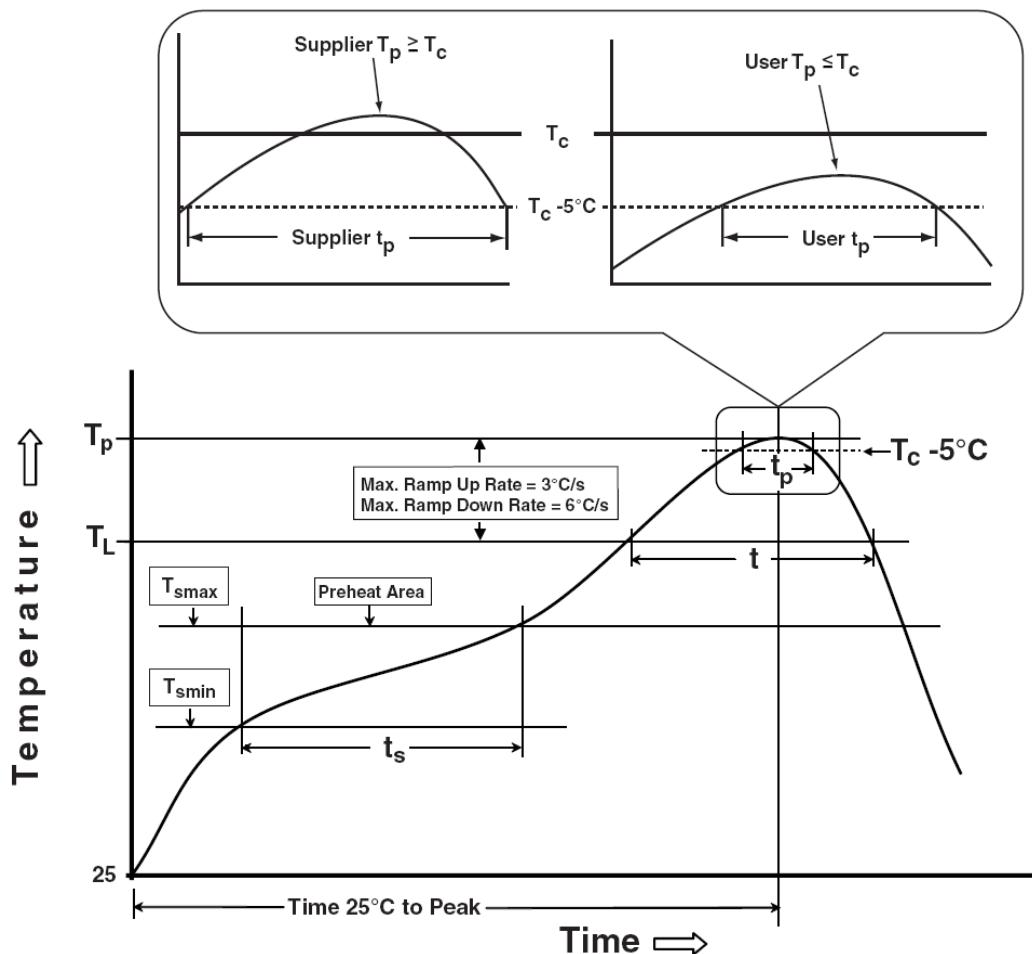
•Dimensions (TO-220F3)

Unit: mm

SYMBOL	min	max	SYMBOL	min	max
A	4.40	4.90	E	14.70	15.30
A1	2.40	3.00	e	2.40	2.70
A2	2.30	3.00	e1	4.95	5.25
b	0.50	0.80	L	12.40	14.20
b1	0.90	1.30	L1	1.80	2.20
c	0.40	0.70	$\varnothing P$	2.90	3.50
D	9.80	10.50			
F	2.70	3.30			



- Classification Profile



● Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak Temperature min (T_{smin}) Temperature max (T_{smax}) Time (T_{smin} to T_{smax}) (t_s)	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds
Average ramp-up rate (T_{smax} to T_p)	3 °C/second max.	3°C/second max.
Liquidous temperature (T_L) Time at liquidous (t_L)	183 °C 60-150 seconds	217 °C 60-150 seconds
Peak package body Temperature (T_p)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_p)** within 5°C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_p to T_{smax})	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.

* Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum.
 ** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.

Table 1. SnPb Eutectic Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test Item	Method	Description
Solder ability	JESD-22, B012	5 SEC., 245°C
HOLT	JESD-22, A108	1000 HRs, Bias@125°C
PCT	JESD-22, A102	168 HRs, 100% RH, 2ATM, 121°C
TCT	JESD-22, A104	500 Cycles, -65 ~ 150°C